Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/752,094	FRAZIER ET AL.
Examiner	Art Unit
Hau V. Phan	3618

SEARCHED				
Class	Subclass	Date	Examiner	
280	11.221 11.3 11.27	3/23/2007	НР	
	11.223			
	11.224	_		
	1.225			
	11.227			
	11.231	•		
	11.233			
	11.28			
	11.19			
	·			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
			<u> </u>	

SEARCH NOT (INCLUDING SEARCH	TES STRATEGY	)
	DATE	EXMR.
•		